

Notice of References Cited

Application/Control No.

08/960,431

Applicant(s)/Patent Under
Reexamination
SUGIYAMA ET AL.

Examiner

Jacob K. Ackun Jr.

Art Unit

3723

Page 1 of 2

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-3,568,377	03-1971	Blohm et al.	451/444
*	B	US-3,594,963	07-1971	Beasley, George A.	51/293
*	C	US-3,710,517	01-1973	Valerio et al.	451/42
*	D	US-3,785,094	01-1974	Holzhauer, Rudolf	451/532
*	E	US-5,154,021	10-1992	Bombardier et al.	451/444
*	F	US-5,172,681	12-1992	Ruark et al.	125/38
*	G	US-5,235,959	08-1993	Frank et al.	125/11.01
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
*	U	Semiconductor International, Mar. 1992, pp.44-48, Peter H. singer, Senior Editor.
*	V	Spin-On Glass for Dielectric Planarization by Satish K. Gupta, distributed through the courtesy of Allied-signal Inc., Milpitas, CA.
*	W	Solid State Technology May 1992, Sematech Inc., Austin, Texas. Planarizing Interlevel Dielectrics by Chemical-Mechanical Polishing.
*	X	Electronics Materials, Mar. 1994, pp91-96.

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Notice of References Cited

Application/Control No.

08/960,431

Applicant(s)/Patent Under
Reexamination
SUGIYAMA ET AL.

Examiner

Jacob K. Ackun Jr.

Art Unit

3723

Page 2 of 2

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
*	U	Speedfam CMP-V Planarization System, The Competitive Edge. 0.35, Micron Line Width Design Rule.
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.